

合同配置清单:

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Nicolet is50 FTIR Spectrometer including:

Nicolet is50 红外光谱仪包括:

- Highest optical throughput due to pinned in place
高性能对针定位光学平台
- Highest signal-to-noise ratio due to superior optical and electronics design
高信噪比设计光学和电子系统
- Touch Point one-touch sampling operation
一键式采样操作系统
- High speed USB 2.0 interface
高速 USB2.0 接口
- Ready for iS50 ABX automatic beamsplitter changer
可配置 iS50 分束器自动切换装置
- Internal storage for 2 additional beamsplitters
可选配内置 3 分束器
- Internal Validation wheel for SPV or ValPro Qualifications
内置 SPV 或 ValPro 仪器性能自检和认证系统
- Includes NIST Traceable Polystyrene and NG11 Glass
标准样品包括 NIST 认证的聚苯乙烯薄膜和 NG11 玻璃
- four position quadraflex source mirror

四位置切换光源聚焦镜

~ Three position Paraflect detector mirror

计算机控制三检测器自动切换系统

- Upgradeable to include iS50 ATR Built-in, wide range diamond ATR
可升级内置式金刚石 ATR, 检测范围至远红外区
- Accepts all smart accessories and many others
适配所有智能附件和其它附件
- Expandable with the iS50 GC-IR and iS50 NIR modules, Ready to accept iS50

Raman Module, Compatible with Continuum FT-IR microscope and TGA accessory

可内置 iS50 拉曼模块, 扩展 iS50 气红和近红外模块,
与 Continuum 红外显微镜和 TGA 联机等

- Optional Smart purge system
可选配智能吹扫控制系统

Vectra™ Interferometer

最新专利 Vectra-Plus™ 干涉仪

- Auto-Tune™
自动调整功能
- Continuous Dynamic Alignment
超高稳定性动态准直 130,000 次/秒控制
- Better than 0.09cm^{-1} spectral resolution
优于 0.09cm^{-1} 分辨率
- Less than 0.07%T deviation ASTM linearity
ASTM 标准线性优于 0.07%T
- Peak-to-Peak Noise $<7.89 \times 10^{-6}$ Abs
峰-峰噪音值小于 7.89×10^{-6} Abs
(在 ASTM 标准线性优于 0.07%T 条件下, 信噪比: 优于 55,000:1)
- Rapid Scan : 65 Spectra/s
基本快速扫描功能: 65 张谱图/秒 (MCT 检测器响应)

Long Lifetime Polaris™ Infrared Source

超长寿命 Polaris™ 专利红外光源

- Automated continuously variable aperture

200 档高精度可变光圈自动控制

Ge on KBr beamsplitter(7,800-350cm⁻¹)

中红外 KBr 分束器

DLaTGS Detector with KBr window(12,500-350cm⁻¹)

DLaTGS 检测器

- 24Bit 500KHz High-speed AD converter

24Bit 500KHz 高速 AD 转换

Sealed and Desiccated Optical Bench(KBr Optics)

密封干燥带湿度显示光学台

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OMNIC Professional Package includes the following:

OMNIC 智能软件包，包括：

- OMNIC Data Manipulation w/Data Collect

OMNIC 数据处理和数据采集

- Auto Analyze feature to perform and report TQ prediction, searching,

Qcheck or Peak Labelling immediately after collection without any need for intervention.

样品光谱采集后自动完成定量建模编辑、搜索、高灵敏度精确鉴定和谱峰标定。

- Touch point software support for iS50 spectrometer and modules

支持 iS50 主机和应用模块一键式快捷操作

- Full-featured report generator and electronic laboratory notebook

实验报告电子版转换

- Auto Report feature to automatically view results, print or add to current notebook.

实时光谱预览和自动解析

- Automatic atmospheric suppression to remove H₂O and CO₂ interferences

自动水气和 CO₂ 校正。

- Complete set of spectral data processing tools

完整的谱图数据处理功能

- Full array of data conversion and correction tools such as Kubelka

Munk, Kramers Kronig and Advanced ATR correction

完整的数据转换和校正功能，包括 K-M 转换、K-K 转换和高级 ATR 校正等

- TQ Professional for quantitative and qualitative method development prediction and deployment.

专业版 TQ 定量和定量分析方法开发

- Customizable Toolbar, Menu, and Options with User Logins

用户自定义工具菜单和设置登录的用户名

- Spectral Search: High-Resolution Library Generation, Customizable Information Fields, Single or

Multiregion Search, Library Management with Over 1400 Spectra in Included Spectra in Included Libraries

光谱检索：高分辨率谱库，用户可自定义检索信息，单

区域或多区域检索，谱库管理，内置 1400 多张标准谱图

- OMNIC Macros\Basic to compile routine tasks into simple

push button operations with access via OMNIC's customizable toolbar

集成化扫描控制面板按钮操作或包含 Macros\Basic 程序的

自定义工作条流程的一键式流程化操作功能

- QCheck correlation for QC/QA verification of samples against one or many reference spectra;

includes standard correlation and unique high sensitivity compare with pass/fail thresholds

QCheck 高灵敏度精确鉴定

- System Performance Verification (SPV) automatically
仪器性能检验 (SPV) 自动监控, 性能校验
- Performance Verification, based on ASTM E1421, to test and document system operation
性能校验 (ASTM E1421 标准, 测试和文档)
- System Suitability to ensure analysis consistency, including your sampling accessory
系统的稳定性测试 (包括附件)
- Easy to set-up parameters, live display of data collection and live spectral preview
实验参数智能设定、实时光谱采集和光谱预览。
- Password protection and user login support
设置登录的用户名和密码保护。
- Extensive on-line help and video tutorials
在线帮助和多媒体教学。

1-3	外延层厚度测试计算软件	1
2	Nicolet iS50 English Language Kit 英语标识	1
3	Power Cord,China 250v 250v 电源接线制式	1
4	300mm Silicon Wafer Analysis Stage & Wafer Analysis Software 300mm 硅片检测分析系统 ~ Software controlled 300 mm stage (PIKE Map300) ~ USB Controlled ~ Driven from OMNIC Wafer Analysis Software ~ Includes Wafer Analysis Software	1
5	12" Wafer Mount for 300mm stage 12 英寸片架	1
6	8" Wafer Insert 8 英寸片架	1
7	6" (150mm) Diameter Wafer Insert for 300mm stage 6 英寸片架	1
8	Computer and Printer 计算机和打印机	1